

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74HC251AP, TC74HC251AF

## 8-Channel Multiplexer (3-state)

The TC74HC251A is a high speed CMOS 8-CHANNEL MULTIPLEXER fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

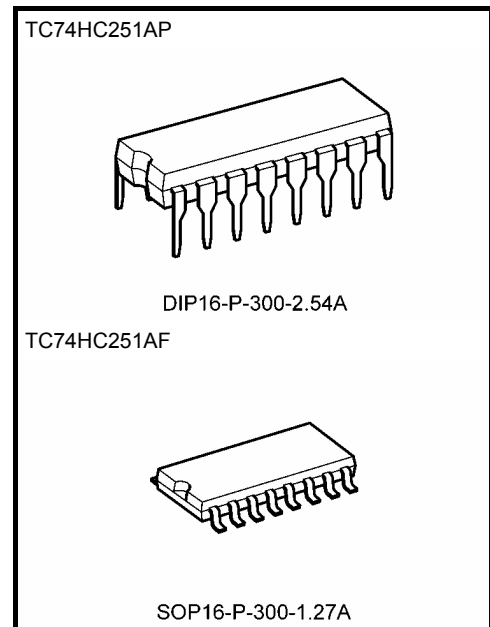
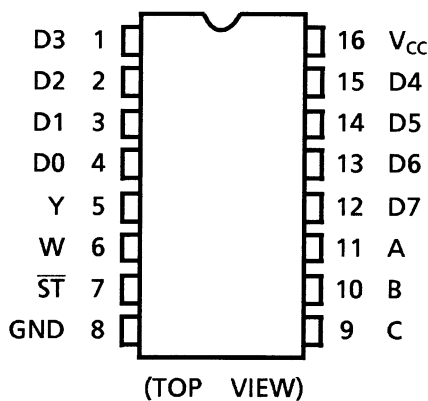
One of eight data input signals (D0-D7) is selected by decoding of the address input (A, B, C). The selected data appears on two outputs; non-inverting (Y) and inverting (W). When the strobe input is held high, both outputs are in the high-impedance state.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

### Features

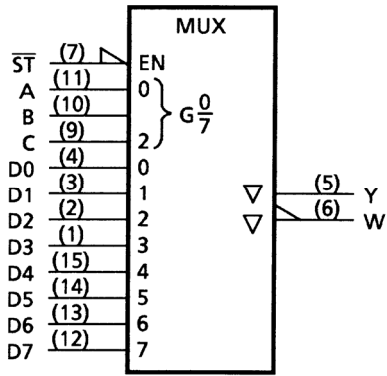
- High speed:  $t_{pd} = 15 \text{ ns}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 4 \mu\text{A}$  (max) at  $T_a = 25^\circ\text{C}$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 4 \text{ mA}$  (min)
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} \text{ (opr)} = 2\sim 6 \text{ V}$
- Pin and function compatible with 74LS251

### Pin Assignment



Weight	
DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)

## IEC Logic Symbol



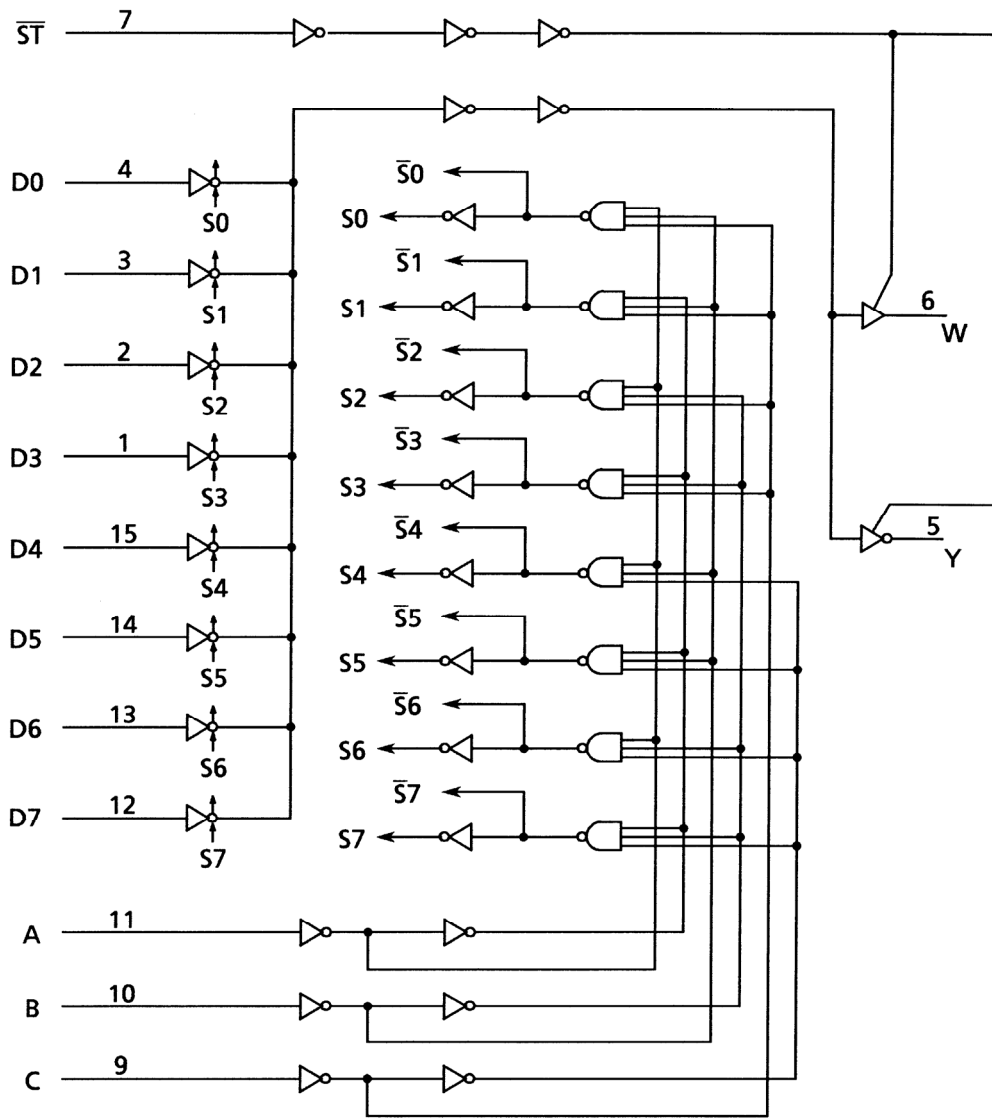
## Truth Table

Inputs				Outputs	
Select			Strobe	Y	W
C	B	A	$\overline{ST}$		
X	X	X	H	Z	Z
L	L	L	L	D0	$\overline{D0}$
L	L	H	L	D1	$\overline{D1}$
L	H	L	L	D2	$\overline{D2}$
L	H	H	L	D3	$\overline{D3}$
H	L	L	L	D4	$\overline{D4}$
H	L	H	L	D5	$\overline{D5}$
H	H	L	L	D6	$\overline{D6}$
H	H	H	L	D7	$\overline{D7}$

X: Don't care

H: High impedance

System Diagram



**Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5~7	V
DC input voltage	$V_{IN}$	-0.5~ $V_{CC} + 0.5$	V
DC output voltage	$V_{OUT}$	-0.5~ $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	$\pm 20$	mA
Output diode current	$I_{OK}$	$\pm 20$	mA
DC output current	$I_{OUT}$	$\pm 25$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 50$	mA
Power dissipation	$P_D$	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	$T_{stg}$	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of  $T_a = -40\sim 65^\circ\text{C}$ . From  $T_a = 65$  to  $85^\circ\text{C}$  a derating factor of  $-10\text{ mW}/^\circ\text{C}$  shall be applied until 300 mW.

**Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2~6	V
Input voltage	$V_{IN}$	0~ $V_{CC}$	V
Output voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	$t_r, t_f$	0~1000 ( $V_{CC} = 2.0\text{ V}$ ) 0~500 ( $V_{CC} = 4.5\text{ V}$ ) 0~400 ( $V_{CC} = 6.0\text{ V}$ )	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
				V <sub>CC</sub> (V)	Min	Typ.	Max	Min		Max
High-level input voltage	V <sub>IH</sub>	—		2.0	1.50	—	—	1.50	—	V
				4.5	3.15	—	—	3.15	—	
				6.0	4.20	—	—	4.20	—	
Low-level input voltage	V <sub>IL</sub>	—		2.0	—	—	0.50	—	0.50	V
				4.5	—	—	1.35	—	1.35	
				6.0	—	—	1.80	—	1.80	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20 μA	2.0	1.9	2.0	—	1.9	—	V
				4.5	4.4	4.5	—	4.4	—	
			I <sub>OH</sub> = -4 mA	4.5	4.18	4.31	—	4.13	—	
				6.0	5.68	5.80	—	5.63	—	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 μA	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
			I <sub>OL</sub> = 4 mA	4.5	—	0.17	0.26	—	0.33	
				6.0	—	0.18	0.26	—	0.33	
3-state off leak current	I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = V <sub>CC</sub> or GND	6.0	—	—	±0.5	—	±5.0	μA	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	6.0	—	—	±0.1	—	±1.0	μA	
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	6.0	—	—	4.0	—	40.0	μA	

### AC Characteristics (C<sub>L</sub> = 15 pF, V<sub>CC</sub> = 5 V, Ta = 25°C, input: t<sub>r</sub> = t<sub>f</sub> = 6 ns)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	t <sub>TLH</sub>	—	—	4	8	ns
	t <sub>THL</sub>					
Propagation delay time (D-Y)	t <sub>pLH</sub>	—	—	14	24	ns
	t <sub>pHL</sub>					
Propagation delay time (D-W)	t <sub>pLH</sub>	—	—	15	24	ns
	t <sub>pHL</sub>					
Propagation delay time (A, B, C-Y)	t <sub>pLH</sub>	—	—	19	31	ns
	t <sub>pHL</sub>					
Propagation delay time (A, B, C-W)	t <sub>pLH</sub>	—	—	19	31	ns
	t <sub>pHL</sub>					
3-state output enable time	t <sub>pZL</sub>	—	—	10	18	ns
	t <sub>pZH</sub>					

## AC Characteristics ( $C_L = 50 \text{ pF}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Ta = 25°C			Ta = -40~85°C		Unit
				Min	Typ.	Max	Min	Max	
Output transition time	$t_{TLH}$ $t_{THL}$	—	2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation delay time (D-Y)	$t_{pLH}$ $t_{pHL}$	—	2.0	—	65	140	—	175	ns
			4.5	—	17	28	—	35	
			6.0	—	14	24	—	30	
Propagation delay time (D-W)	$t_{pLH}$ $t_{pHL}$	—	2.0	—	70	140	—	175	ns
			4.5	—	18	28	—	35	
			6.0	—	15	24	—	30	
Propagation delay time (A, B, C-Y)	$t_{pLH}$ $t_{pHL}$	—	2.0	—	80	180	—	225	ns
			4.5	—	23	36	—	45	
			6.0	—	19	31	—	38	
Propagation delay time (A, B, C-W)	$t_{pLH}$ $t_{pHL}$	—	2.0	—	80	180	—	225	ns
			4.5	—	23	36	—	45	
			6.0	—	19	31	—	38	
3-state output enable time	$t_{pZL}$ $t_{pZH}$	—	2.0	—	40	105	—	130	ns
			4.5	—	13	21	—	26	
			6.0	—	10	19	—	22	
3-state output disable time	$t_{pLZ}$ $t_{pHZ}$	—	2.0	—	25	105	—	130	ns
			4.5	—	13	21	—	26	
			6.0	—	11	19	—	22	
Input capacitance	C <sub>IN</sub>	—	—	5	10	—	10	pF	
Power dissipation capacitance	C <sub>PD</sub> (Note)	—	—	69	—	—	—	pF	

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

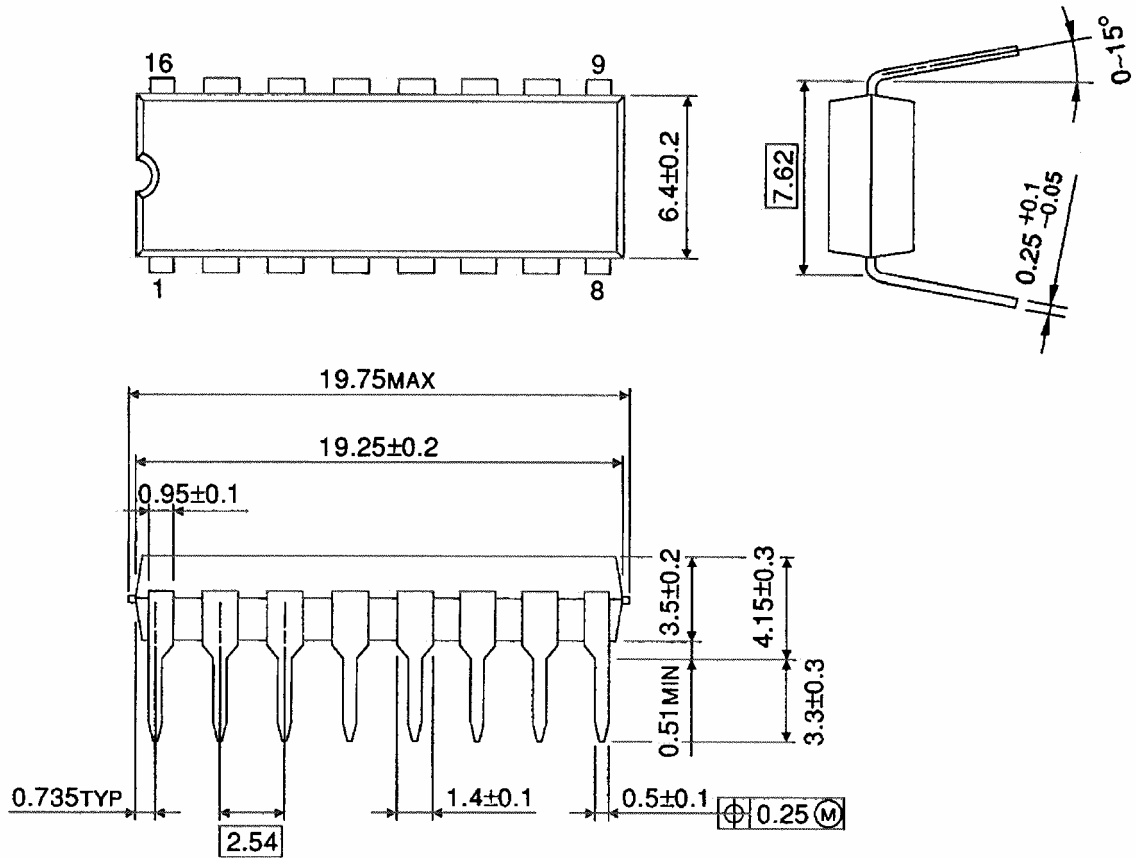
Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## Package Dimensions

DIP16-P-300-2.54A

Unit : mm

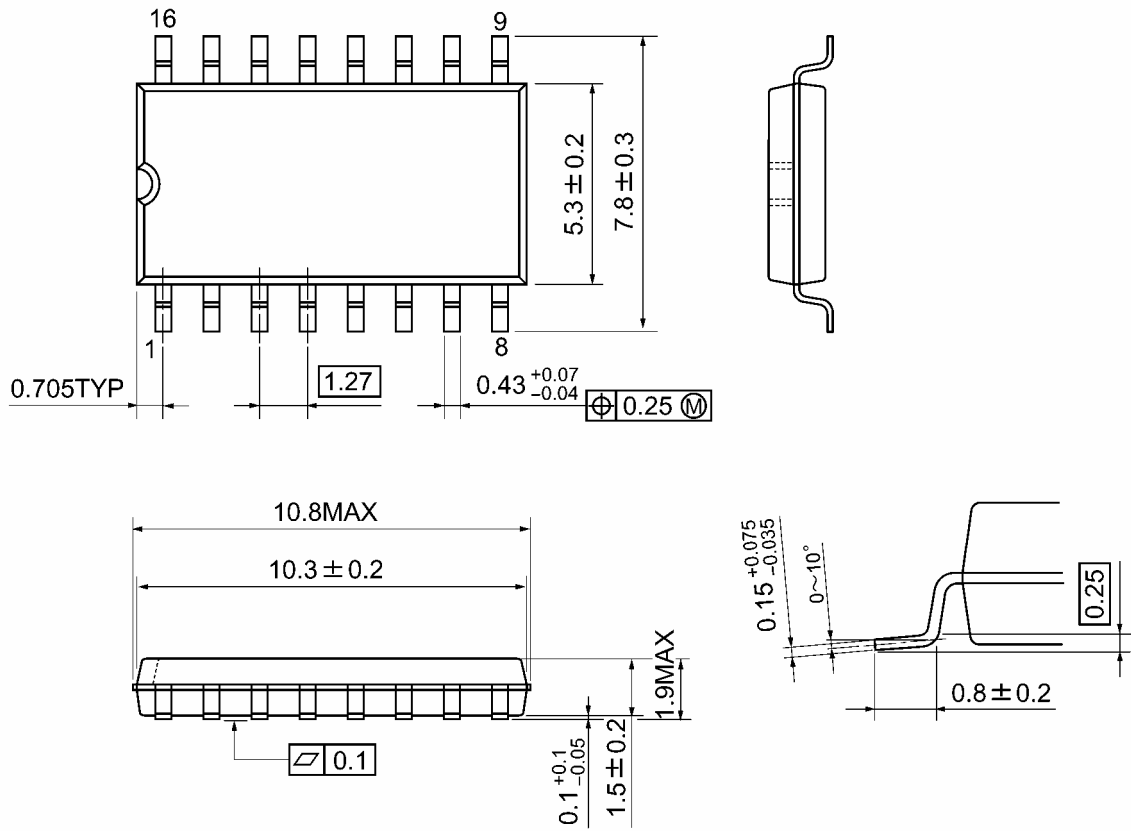


Weight: 1.00 g (typ.)

**Package Dimensions**

SOP16-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)



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20070701-EN GENERAL

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